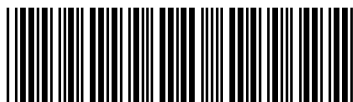


**Search Notes**

Application/Control No.

10/803,087

Examiner

Rudy Zervigon

Applicant(s)/Patent under  
Reexamination

HASEGAWA ET AL.

Art Unit

1792

**SEARCHED**

Class	Subclass	Date	Examiner
118	715	9/26/2009	RZ
118	641	9/26/2009	RZ
118	69	9/26/2009	RZ

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
<b>118</b>	<b>715</b>	<b>9/26/2009</b>	<b>RZ</b>
118	641	9/26/2009	RZ
118	69	9/26/2009	RZ

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
("thermal conductivity") and (chamber or reactor or vessel)).clm. and (wafer or substrate or semiconductor).clm.	9/26/2009	RZ
2 and heat\$3.clm. and cool\$3.clm.	9/26/2009	RZ